

**Search Notes**

Application/Control No.

10/020,051

Examiner

Nhan T. Tran

Applicant(s)/Patent under  
Reexamination

FUJII ET AL.

Art Unit

2615

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST SEARCH (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB)	1/19/2006	NT
348/345-357 (text search - see search history printout)	1/19/2006	NT
348/220.1 (text search - see search history printout)	1/20/2006	NT